

<b>Notice of References Cited</b>	Application/Control No. 10/612,396	Applicant(s)/Patent Under Reexamination MAUNEY ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,905,956 a	05-1999	Young et al.	455/435.1
*	B	US-6,108,540 a	08-2000	Sonti et al.	455/433
*	C	US-5,673,308	09-1997	Akhavan, Hamid	455/461
*	D	US-6,029,065 A	02-2000	Shah, Bharat	455/414.4
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